Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination			
10/574,528	LEE ET AL.			
Examiner	Art Unit			

Patricia T. Nguyen

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SEARCHED					_
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Class	Subclass	Date 1/6/2008		Examiner PN	
330	142				
	302				
	296				
333	214				
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INTERFERENCE SEARCHED						
Cla	ISS	Subclass	Date		Examiner	
33	30	142	1/6/2008		PN	
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		296				
	333.	/214				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	D	ATE	EXMR	
EAST	1/6	/2008	PN	